

Search Notes**Application/Control No.**

10/664,264

Examiner

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Applicant(s)/Patent under Reexamination

WERTENBRUCH ET AL.

Art Unit

2134

SEARCHED

Class	Subclass	Date	Examiner
380	255	2/17/2007	ECT
713	153	2/17/2007	ECT
380	257	2/17/2007	ECT
380	41	2/17/2007	ECT
709	228	2/17/2007	ECT
709	221	2/17/2007	ECT
709	220	2/17/2007	ECT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	2/17/2007	ECT
INVENTOR SEARCH - PALM	2/17/2007	ECT
NPL - IEEE XPLOR	2/17/2007	ECT
All claims were reviewed for 101 rejection	2/17/2007	ECT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner